

Search Notes

Application/Control No.

10/608,151

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

PATEL ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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